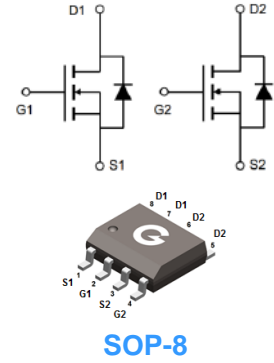


### Features

- Advanced trench technology
- Super low gate charge
- Fast switching speed

HF



### Mechanical Data

- Case: SOP-8
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208

### Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
GBLN6606-S8	SOP-8	4000 pcs / Tape & Reel	GBLN6606

### Maximum Ratings (@ T<sub>A</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V <sub>DSS</sub>	60	V
Gate-to-Source Voltage	V <sub>GSS</sub>	±20	V
Continuous Drain Current (T <sub>C</sub> = 25°C)	I <sub>D</sub>	5.2	A
Continuous Drain Current (T <sub>A</sub> = 25°C) <sup>*1</sup>		3	A
Continuous Drain Current (T <sub>A</sub> = 100°C) <sup>*1</sup>		1.9	A
Pulsed Drain Current (t <sub>p</sub> = 10μs, T <sub>A</sub> = 25°C)	I <sub>DM</sub>	30	A
Single Pulse Avalanche Energy <sup>*3</sup>	E <sub>AS</sub>	10	mJ
Power Dissipation (T <sub>C</sub> = 25°C)	P <sub>D</sub>	5	W
Power Dissipation (T <sub>A</sub> = 25°C) <sup>*1</sup>		1.5	W
Operating Junction Temperature Range	T <sub>J</sub>	-55 ~ +150	°C
Storage Temperature Range	T <sub>STG</sub>	-55 ~ +150	°C

### Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance Junction-to-Case	R <sub>θJC</sub>	-	21	25	°C/W
Thermal Resistance Junction-to-Air <sup>*1</sup>	R <sub>θJA</sub>	-	66	83	°C/W

### Electrical Characteristics (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	60	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 60V, V_{GS} = 0V$	-	-	1	$\mu A$
$I_{GSS}$	Gate-Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$R_{DS(ON)}$	Drain-Source On-resistance <sup>*2</sup>	$V_{GS} = 10V, I_D = 3A$	-	60	80	m $\Omega$
		$V_{GS} = 4.5V, I_D = 2A$	-	70	95	m $\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	1.4	2	V
$R_G$	Gate Resistance	$V_{GS} = 0V, f = 1MHz$	-	3	-	$\Omega$
<b>Dynamic Characteristics</b>						
$C_{ISS}$	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1.0MHz$	-	522	-	pF
$C_{OSS}$	Output Capacitance					
$C_{RSS}$	Reverse Transfer Capacitance					
<b>Switching Characteristics</b>						
$t_{d(ON)}$	Turn-on Delay Time <sup>*4</sup>	$V_{DD} = 30V$ $V_{GS} = 10V$ $I_D = 3A$ $R_G = 3\Omega$	-	4	-	ns
$t_r$	Turn-on Rise Time <sup>*4</sup>					
$t_{d(OFF)}$	Turn-Off Delay Time <sup>*4</sup>					
$t_f$	Turn-Off Fall Time <sup>*4</sup>					
$Q_G$	Total Gate-Charge	$V_{DD} = 30V$ $V_{GS} = 10V$ $I_D = 3A$	-	15	-	nC
$Q_{GS}$	Gate to Source Charge					
$Q_{GD}$	Gate to Drain (Miller) Charge					
<b>Source-Drain Diode Characteristics</b>						
$V_{SD}$	Diode Forward Voltage <sup>*2</sup>	$I_{SD} = 3A, V_{GS} = 0V$	-	0.8	1.2	V
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 3A, V_{GS} = 0V$ $di/dt = 100A/\mu s$	-	20	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	15	-	nC

Notes:

- The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper
- The data tested by pulsed, pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$
- The  $E_{AS}$  data shows Max. rating. The test condition is  $V_{DD} = 30V, V_{GS} = 10V, L = 0.5mH$
- Guaranteed by design, not subject to production

Ratings and Characteristics Curves (@  $T_A = 25^\circ\text{C}$  unless otherwise specified)

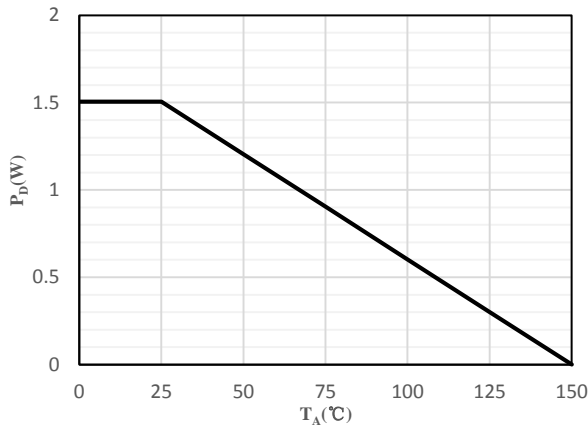


Fig 1 Power Dissipation

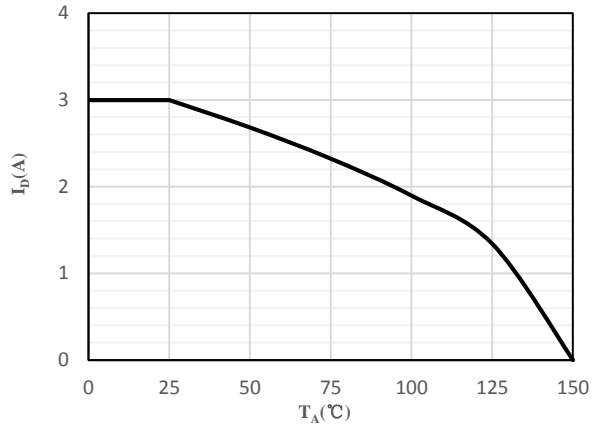


Fig 2 Drain Current

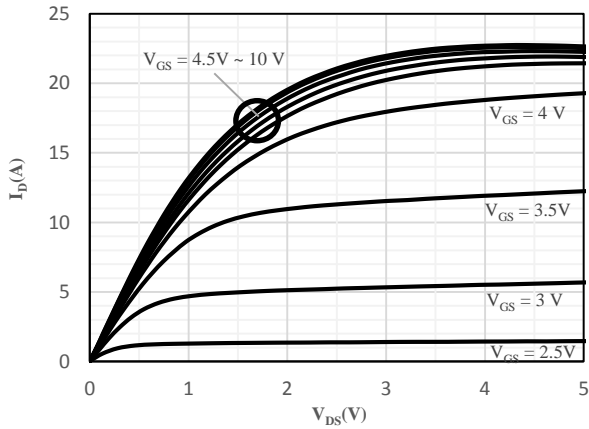


Fig 3 Typical Output Characteristics

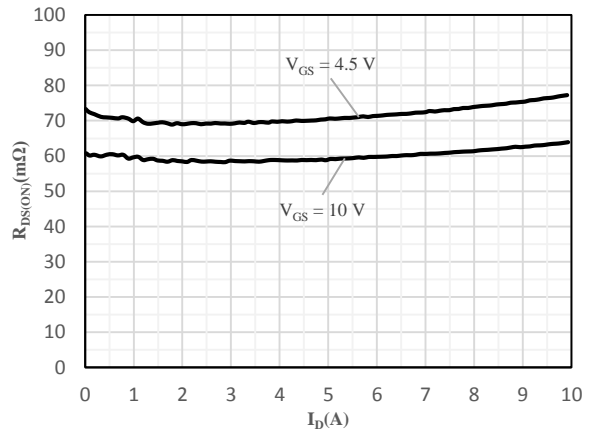


Fig 4 On-Resistance vs. Drain Current and Gate Voltage

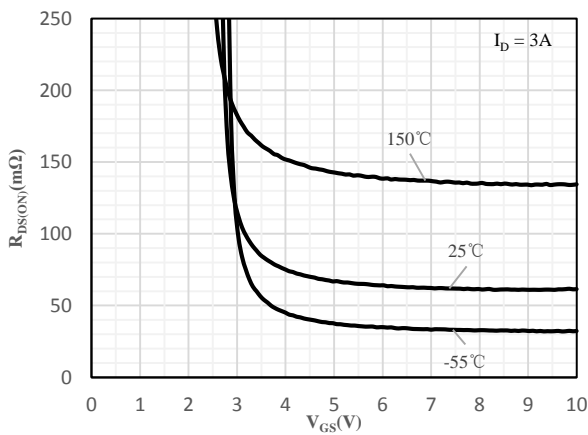


Fig 5 On-Resistance vs. Gate-Source Voltage

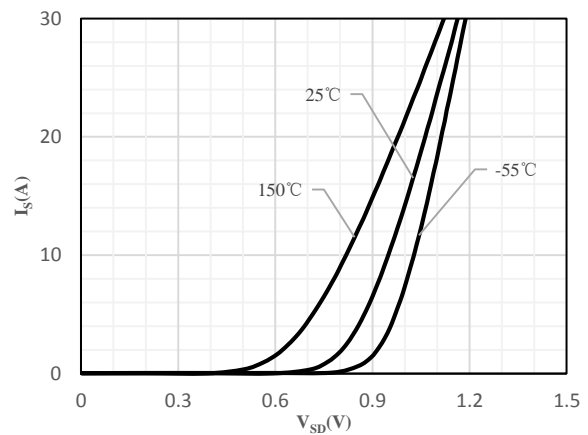


Fig 6 Body-Diode Characteristics

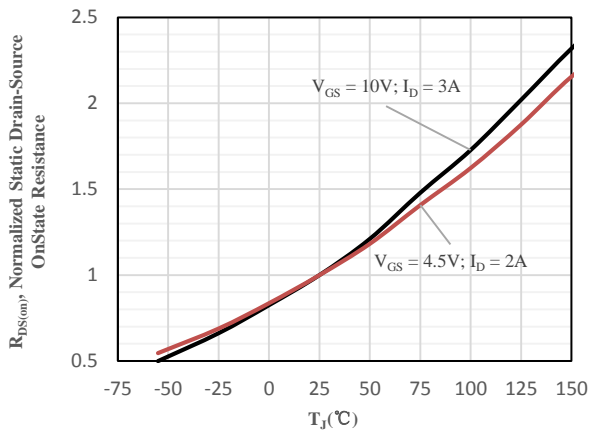


Fig 7 Normalized On-Resistance vs. Junction Temperature

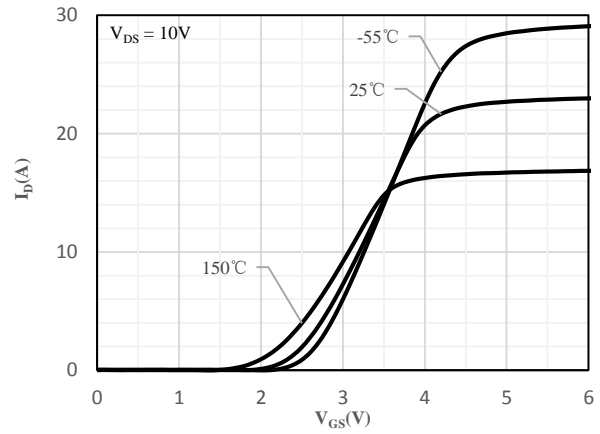


Fig 8 Transfer Characteristics

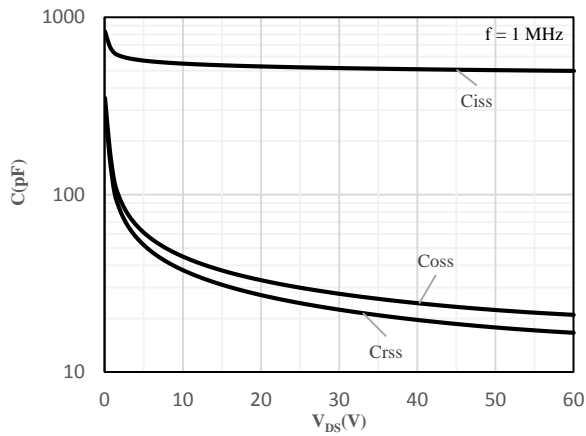


Fig 9 Capacitance Characteristics

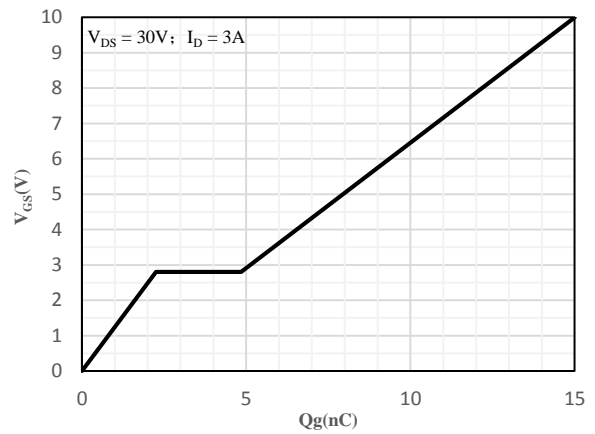


Fig 10 Gate-Charge Characteristics

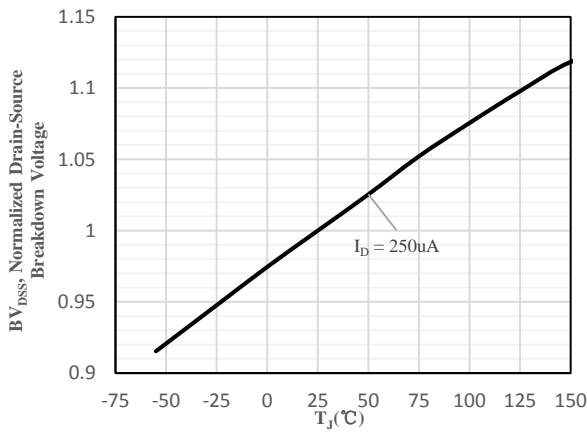


Fig 11 Normalized Breakdown Voltage vs. Junction Temperature

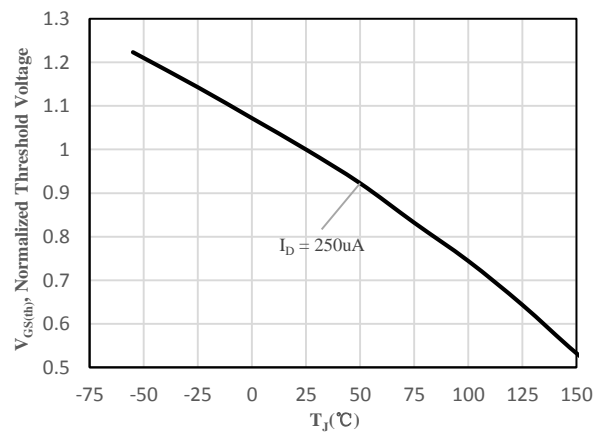


Fig 12 Normalized  $V_{GS(th)}$  vs. Junction Temperature

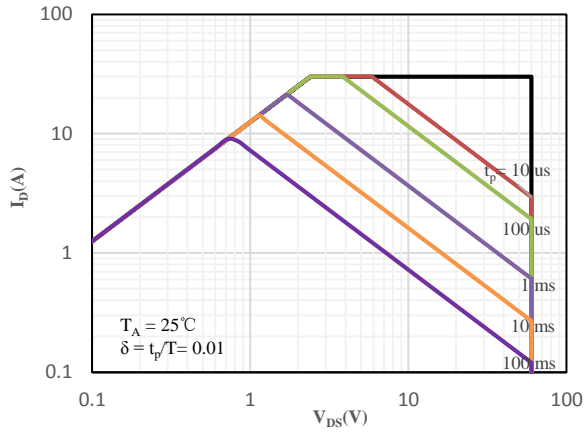


Fig 13 Safe Operating Area

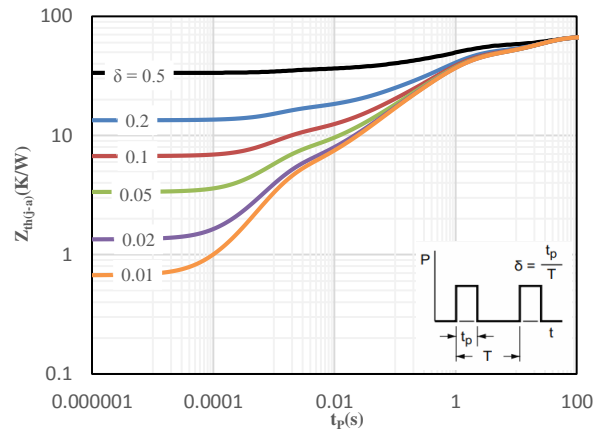
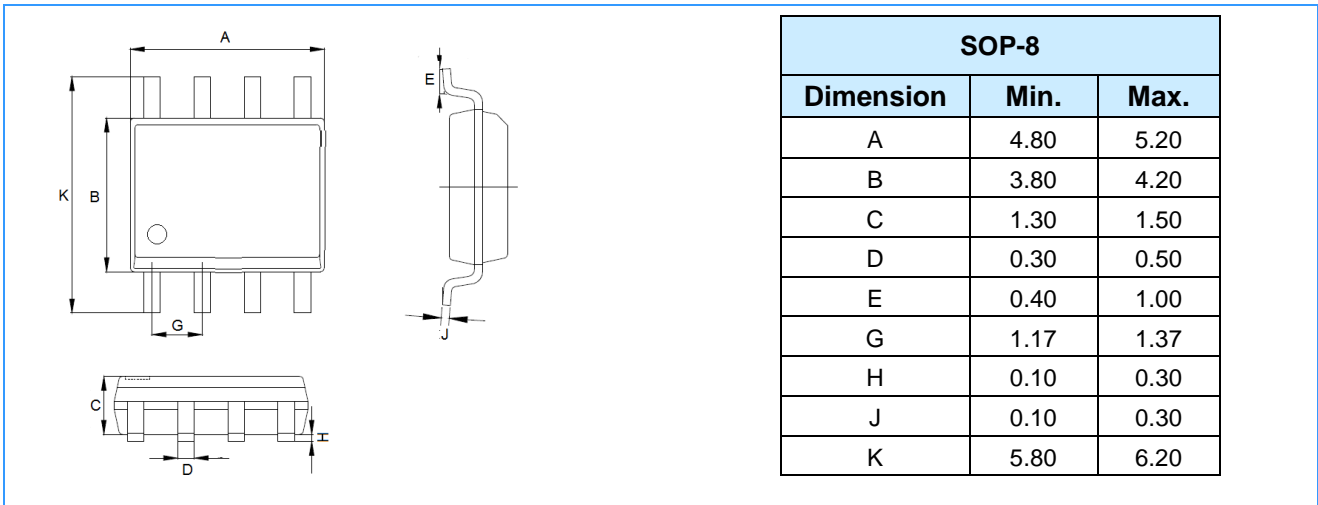
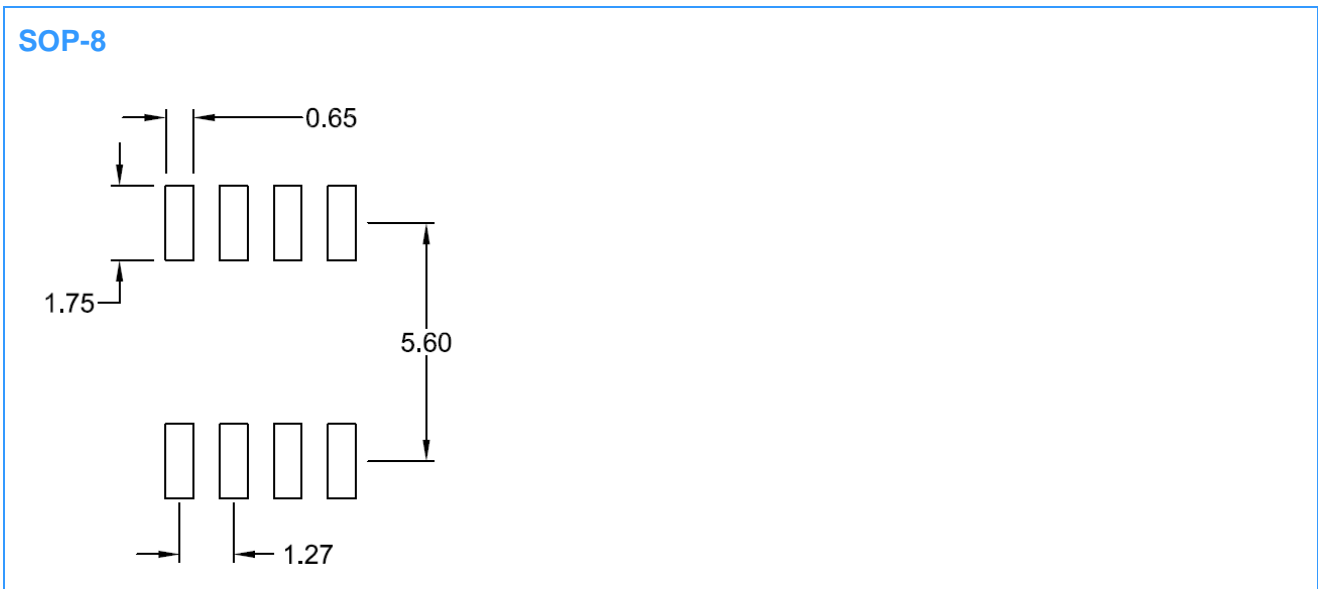


Fig 14 Maximum transient thermal impedance

**Package Outline Dimensions** (Unit: mm)



**Mounting Pad Layout** (Unit: mm)



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